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# EE4280 Lecture 9: Noise

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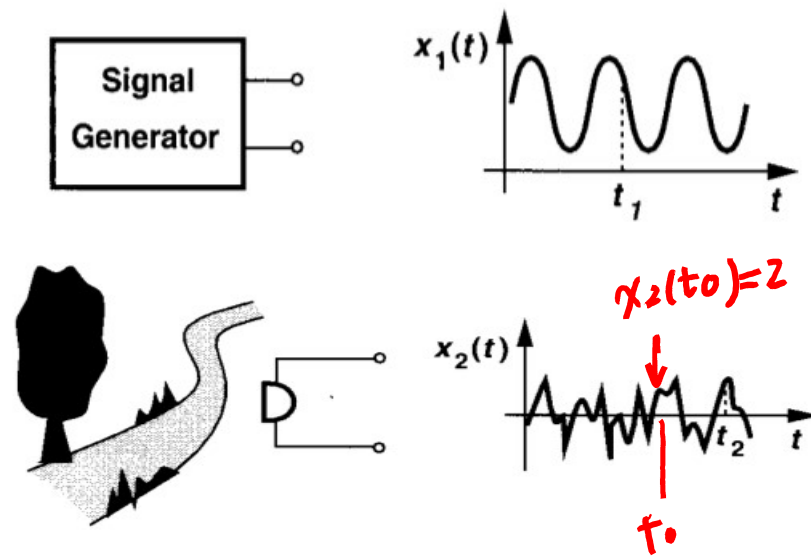
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# What is Noise?

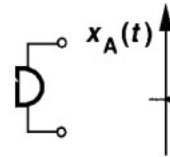
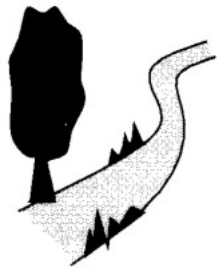
Noise is a random process. We consider a phenomenon random because we do not know everything about it, or simply because we do not need to know everything about it.



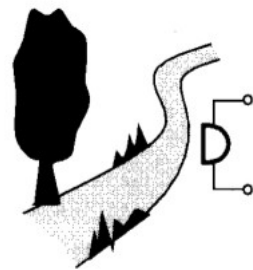
Since the instantaneous noise amplitude is not known, we resort to 'statistical' models, i.e., some properties that can be predicted.

# Statistical Characterization

## 1. Mean and Average Power



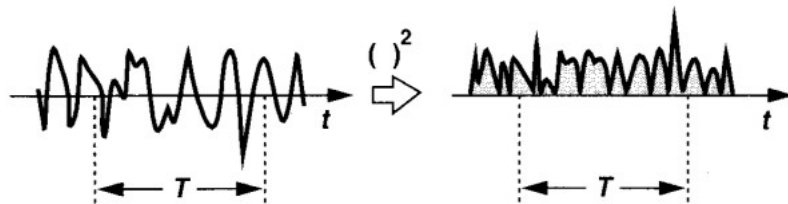
$$\lim_{T \rightarrow \infty} \frac{1}{T} \int_T x_A(t) dt = \overline{x_A} = 0$$



$$\lim_{T \rightarrow \infty} \frac{1}{T} \int_T x_A^2(t) dt = \overline{x_A^2} = 25 \mu V^2 = (5 \text{ mV}_{\text{rms}})^2$$

$$\overline{x_B^2} = (15 \text{ mV})^2$$

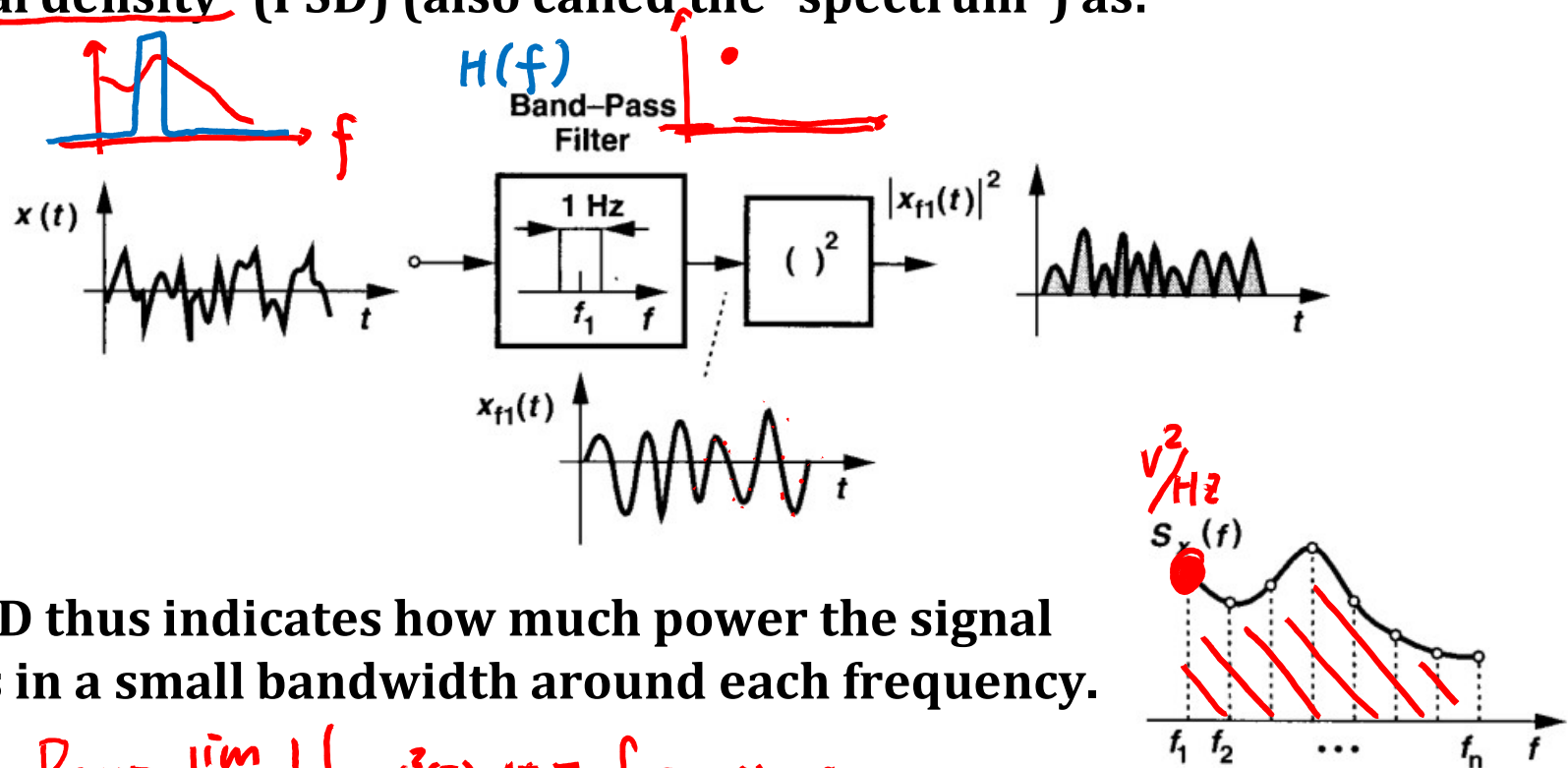
Larger fluctuations mean that the noise is 'stronger'



# Statistical Characterization

## 2. Frequency Domain

For random signals, the concept of Fourier transform cannot be directly applied. But we still know that men carry less high-frequency components in their voice than women do. We define the “power spectral density” (PSD) (also called the “spectrum”) as:



The PSD thus indicates how much power the signal carries in a small bandwidth around each frequency.

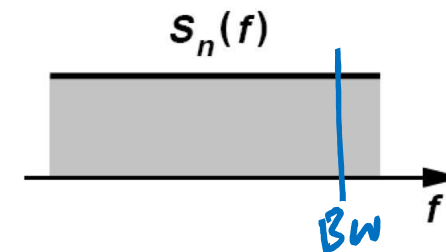
$$P_{av} = \lim_{T \rightarrow \infty} \frac{1}{T} \int_T x^2(\tau) d\tau = \int S_x(f) df$$

# Statistical Characterization

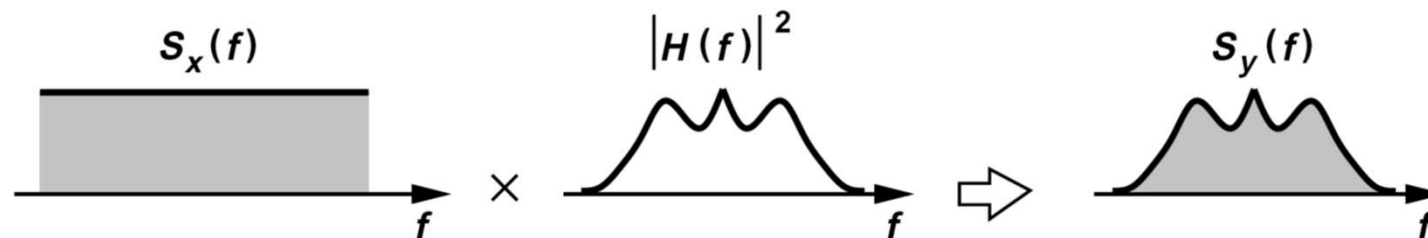
- What is the unit of  $S_n(f)$ ?
- What is the total noise power?

A flat spectrum is called 'white'

- Is the total noise power infinite?



## Important Theorem



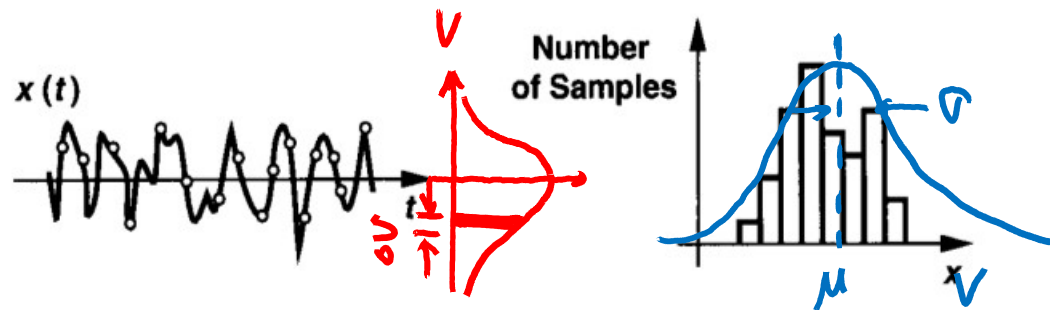
If a signal with spectrum  $S_x(f)$  is applied to a linear time-invariant system with transfer function  $H(s)$ , the output spectrum is given by

$$S_Y(f) = S_X(f)|H(f)|^2$$

# Statistical Characterization

## 3. Amplitude Distribution

By sampling the time-domain waveform for a long time, we can construct a “probability density function” (PDF). The PDF in essence indicates “how often” the amplitude is between certain limits.



For example, a Gaussian distribution is defined by a mean and a standard deviation. We say the noise amplitude rarely exceeds  $4\sigma$ .

Note: Generally PDF and PSD bear no relationship.

Thermal Noise: Gaussian, white

Flicker Noise: Gaussian, not white

# Correlated and Uncorrelated Sources

Can we use superposition for average noise power from a few noise components?

$$P_{av} = \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} [x_1(t) + x_2(t)]^2 dt$$

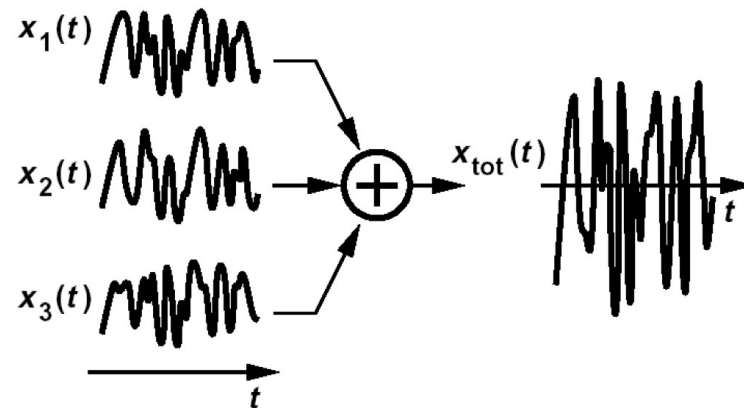
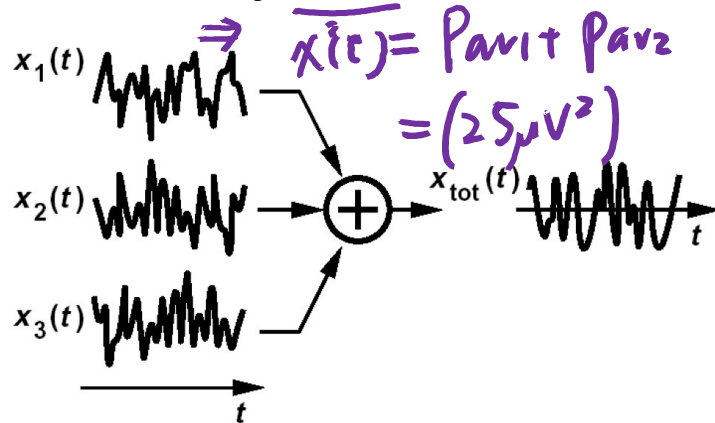
$$x(t) = x_1(t) + x_2(t) \quad = \lim_{T \rightarrow \infty} \frac{1}{T} \int (x_1^2(t) + \underline{2x_1(t)x_2(t)} + x_2^2(t)) dt$$

$$\lim_{T \rightarrow \infty} \frac{1}{T} \int_T x(t) dt = \lim_{T \rightarrow \infty} \frac{1}{T} \int_T (x_1(t) + x_2(t)) dt = P_{av1} + P_{av2}$$

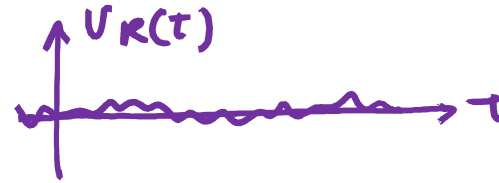
$$\overline{x(t)} = \overline{x_1(t)} + \overline{x_2(t)} = 0 \quad \overline{x_1^2(t)} = (3mV_{rms})^2 + \underbrace{2x_1(t)x_2(t)}_{\text{wavy} \rightarrow 0}$$

$$\overline{x_2^2(t)} = (4mV_{rms})^2 \quad \text{if } x_1(t) \text{ and } x_2(t) \text{ are independent to E.O.}$$

We occasionally encounter correlated sources:

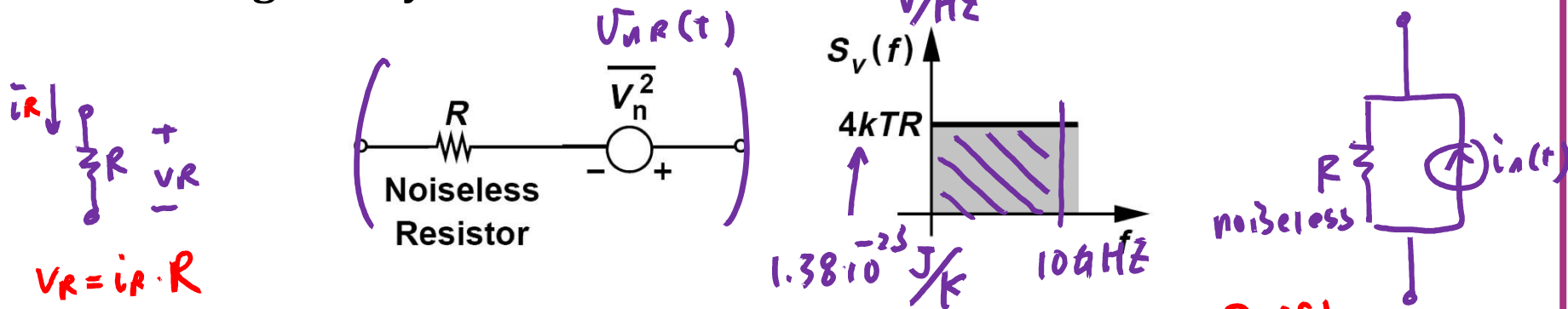


# Types of Noise



## 1. Thermal Noise in Resistors

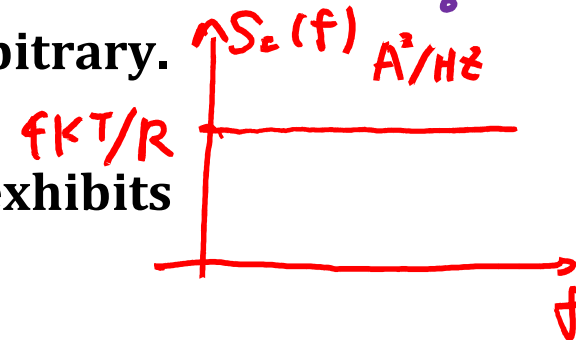
Random movement of charge carriers in a resistor causes fluctuations in the current. The PDF is Gaussian because there are so many carriers. The PSD is given by:



Note that the polarity of the voltage source is arbitrary.

Example: A 50- $\Omega$  resistor at room temperature exhibits

$$S_v(f) = 4 \cdot k \cdot T \cdot 50 = (91 nV)^2 / Hz$$

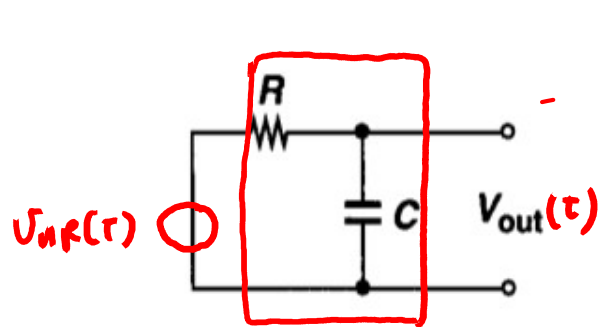


If the resistor is used in a system with 10-GHz bandwidth, then it contributes a total rms voltage of

$$(91 nV)^2 / Hz \cdot 10 GHz = (91 \mu V_{rms})^2$$



# Example: Noise Spectrum and Total Noise Power



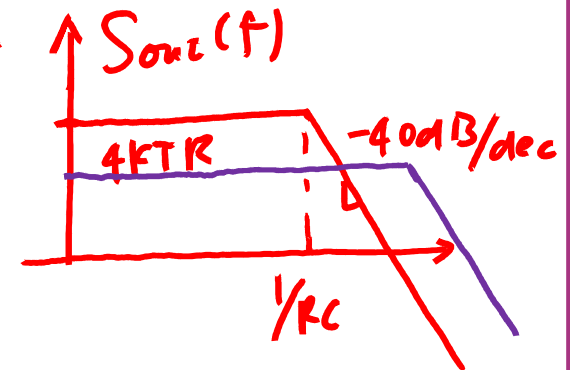
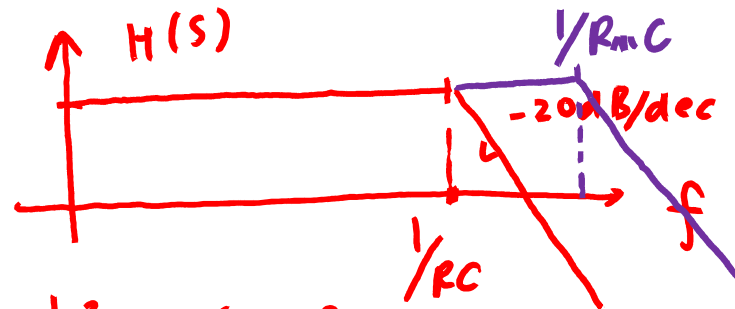
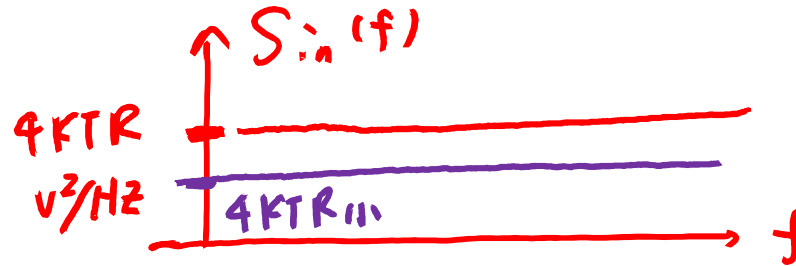
$$\frac{V_{out}}{V_R}(s) = \frac{1}{1 + sRC}$$

$$S_{out}(f) = S_{in}(f) \left| \frac{1}{1 + sRC} \right|^2 = \frac{4KTR}{1 + (\omega RC)^2}$$

$$P_{n,out} = \int S_{out}(f) df = \frac{KT}{C}$$

For  $R=50 \Omega$  and  $C=1 \text{ pF}$ :

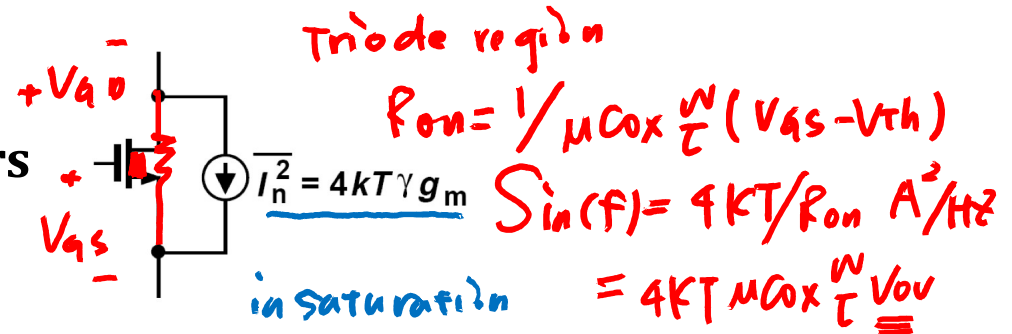
$$= (6.25 \text{ mV}_{rms})^2$$



Trade-offs between noise, area, speed, and power

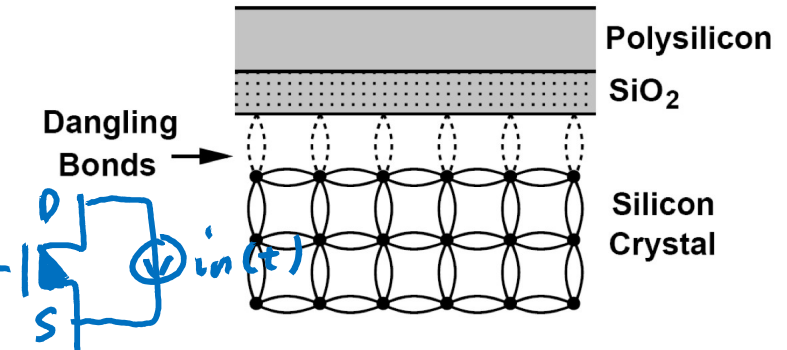
# Types of Noise

## 2. Thermal Noise in Transistors



## 3. Flicker Noise in Transistors

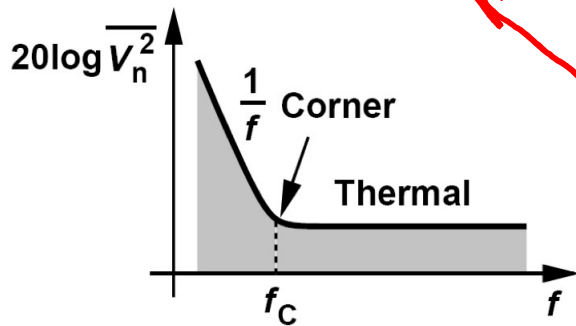
In MOSFETs, the extra energy states at the interface between silicon and oxide trap and release carriers randomly and at different rates. The noise in the drain current is Gaussian, but its spectrum is given by:



$V_n(t)$

$$S_{unf}(f) = \frac{K}{C_{ox} \cdot W \cdot L \cdot f}$$

$S_{in}(f) \propto 4kT V_{ov}$   
 $= 4kT \frac{K}{C_{ox} W L} V_{ov} g_m$   
 $A^2 / Hz$

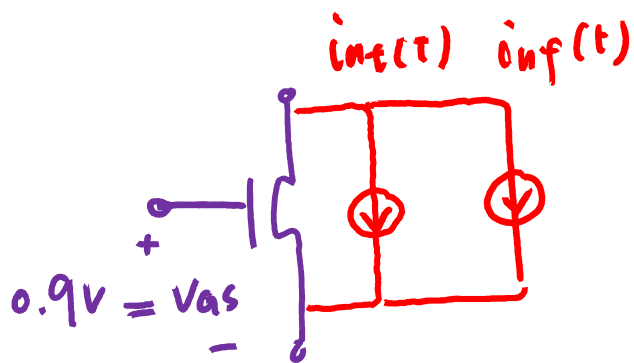
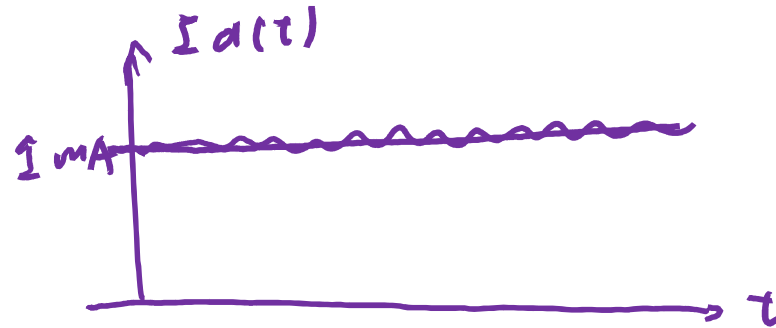
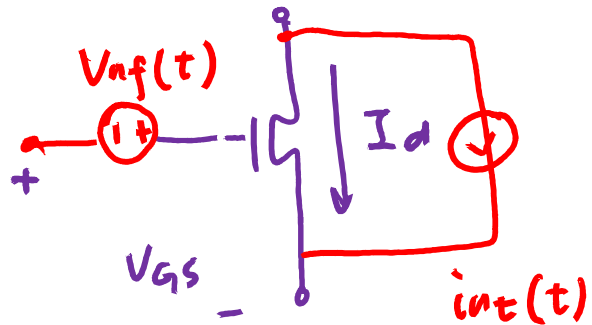


Where k is a constant and its value varies depending on how 'clean' the device is. We often characterize the noise by considering its frequency.

$S_{in}(f) = \frac{K g_m^2}{C_{ox} W L f} A^2 / Hz$

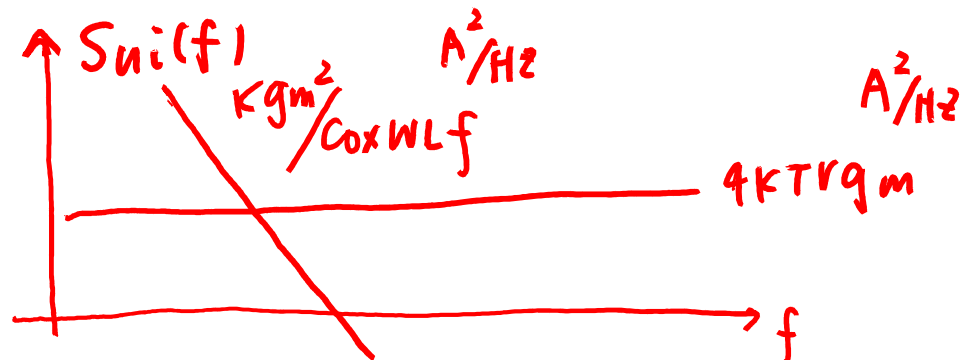
# Example: A Current Source

Total noise in the drain current for a band from 1 kHz to 1 MHz

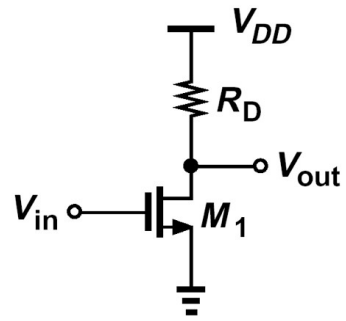


$$i_d(t) = 1 \text{ mA} + \underline{\dot{v}_{n1}(t) + \dot{v}_{n2}(t)}$$

$$\dot{v}_n(t) = \dot{v}_{n1}(t) + \dot{v}_{n2}(t)$$

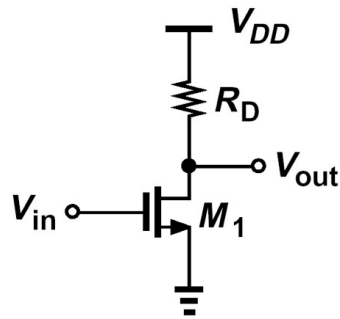


# Common-Source Stage



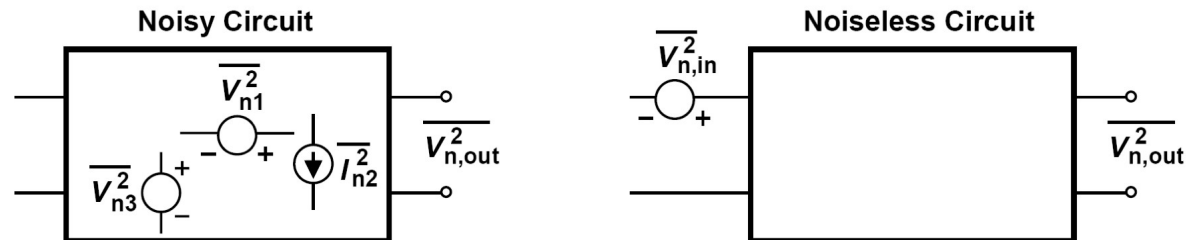


# Common-Source Stage



$$\overline{V_{n,out}^2} =$$

**Input-Referred Noise** is the noise voltage or current that, when applied to the input of the noiseless circuit, generates the same output noise as the actual circuit does.



$$\overline{V_{n,in}^2} =$$

# Common-Source Stage

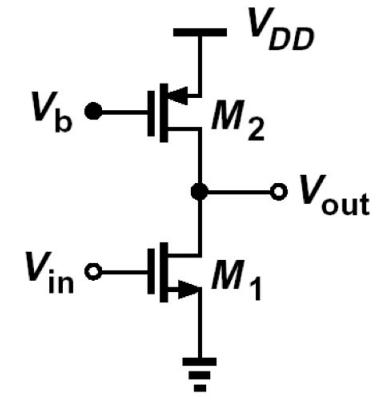
$$\overline{V_{n,in}^2} = 4kT \left( \frac{2}{3g_m} + \frac{1}{g_m^2 R_D} \right) + \frac{K}{C_{ox} W L f}$$

Why does the noise decrease as  $R_D$  increases?

With a current-source load:

$$\overline{V_{n,out}^2} =$$

$$\overline{V_{n,in}^2} =$$



Consider BW limitation from  $C_L$  and a low-frequency signal  $V_m$  at input:

$$P_{n,out} =$$

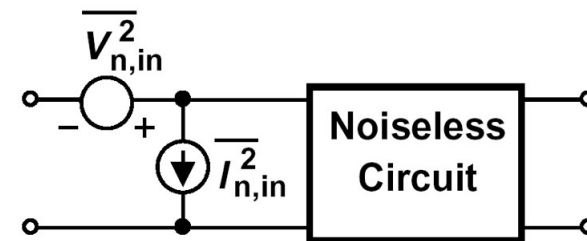
$$SNR_{out} =$$

How to reduce the noise?

Trade-offs between speed, power, and voltage headroom

## Input-Referred Noise

In general, we need both a voltage source and a current source at the input to model the circuit noise.

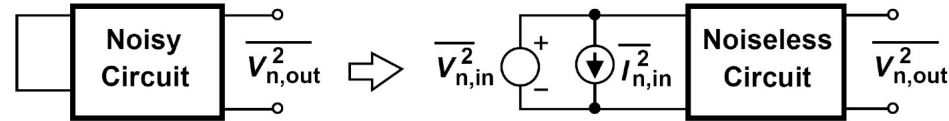


If the source impedance is high with respect to the input impedance of the circuit, then both must be considered.

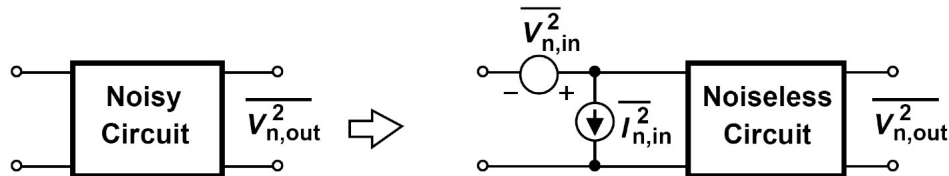


# How To Calculate Input-Referred Noise?

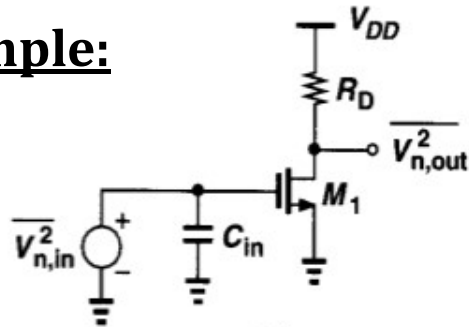
With  $Z_S=0$ :



With  $Z_S=\infty$ :

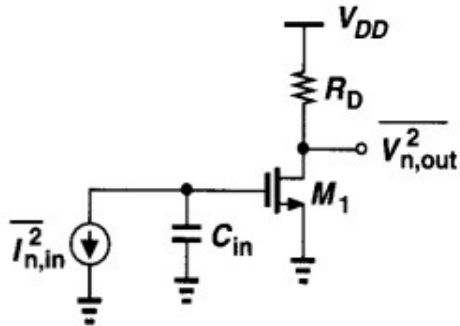


Example:



$$\overline{V_{n,in}^2} =$$

$$\overline{V_{n,out}^2} = \overline{I_{n,in}^2}$$



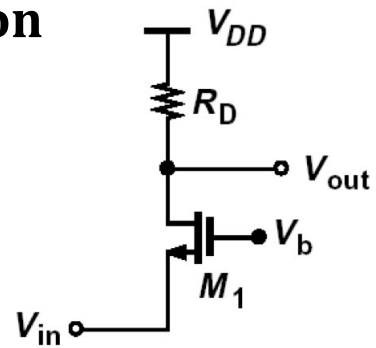
$$\overline{V_{n,out}^2} =$$

$$\overline{I_{n,in}^2} =$$

**With arbitrary  $Z_S$**

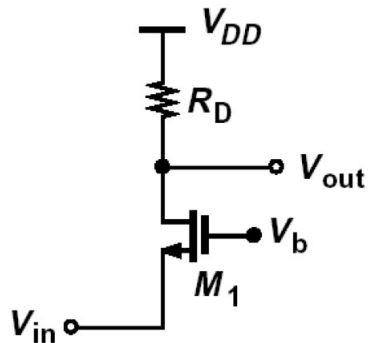
# Common-Gate Stage

Basic operation



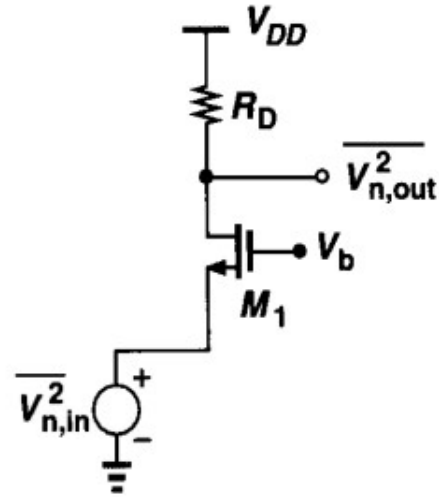
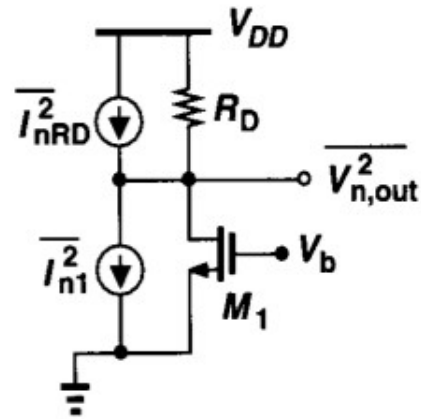
## Common-Gate Stage

Due to the low input impedance, the input-referred noise current is not negligible even at low frequencies



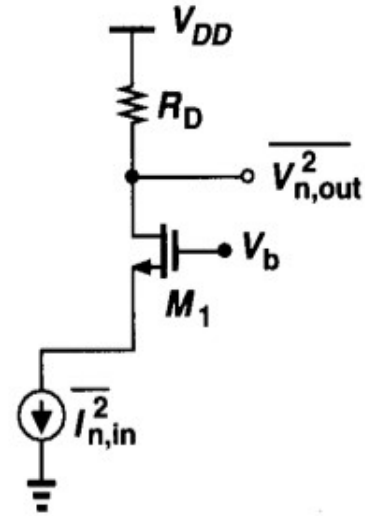
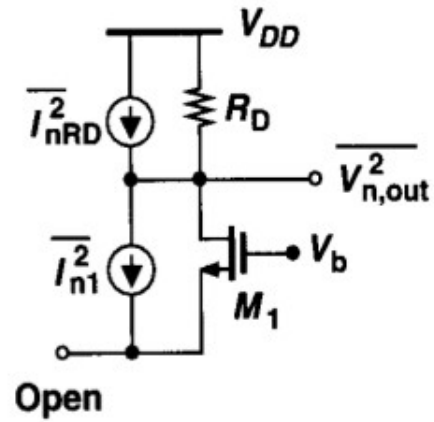
# Common-Gate Stage

For  $Z_S=0$



# Common-Gate Stage

For  $Z_S = \infty$

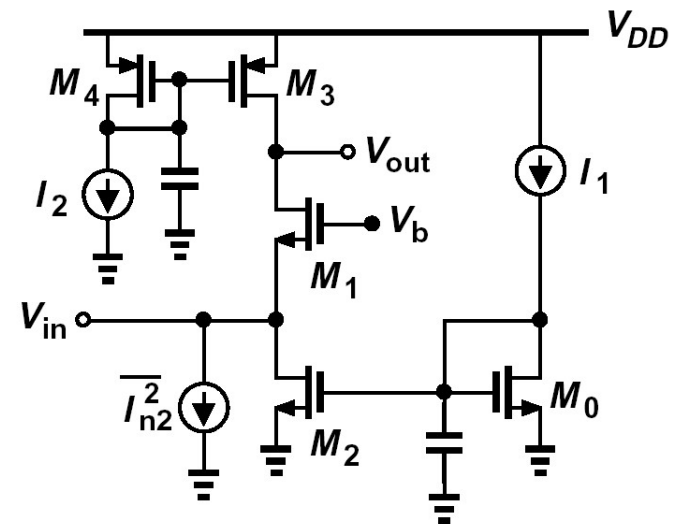


# Current Source

The bias current source often contributes significant noise.

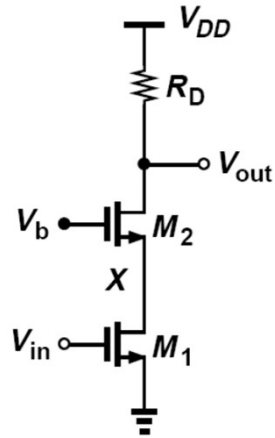
## Example:

- Capacitor  $C_0$  shunts the noise generated by  $M_0$  to ground.
- Noise from  $M_2$ :

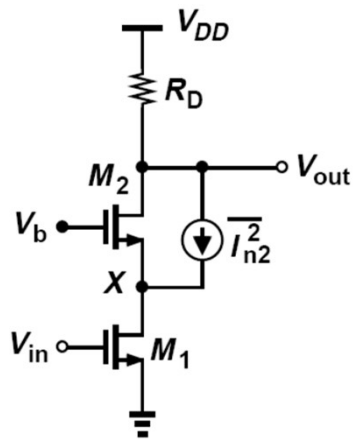


# Cascode Stage

## Basic operation



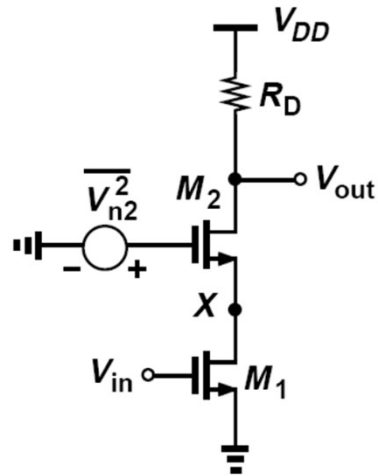
## The effect of noise of M2





# Cascode Stage

With capacitance at node X

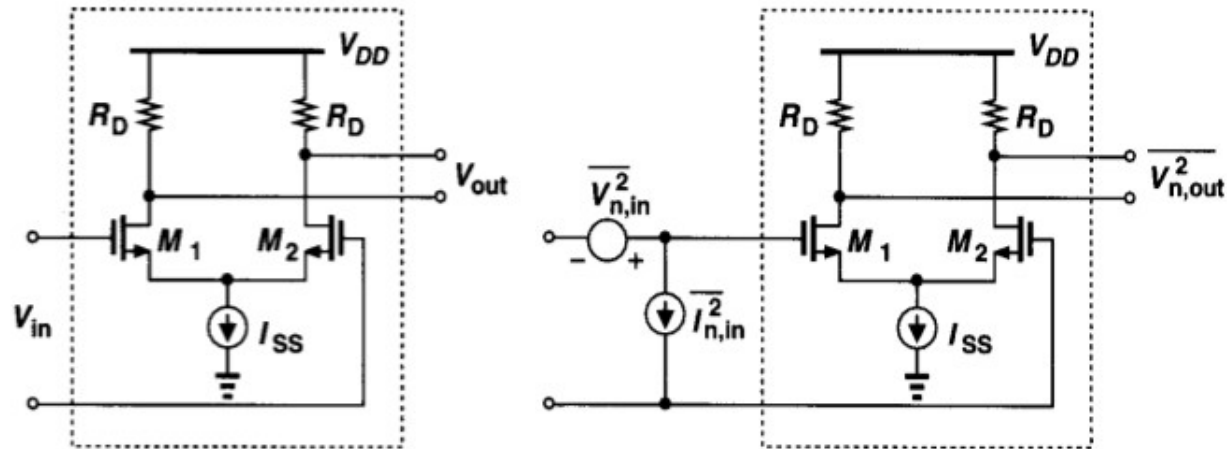


At high frequencies:

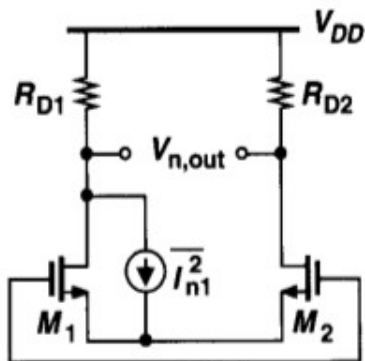
- Output noise is increased
- The gain from  $V_{in}$  to  $V_{out}$  is decreased

# Differential Pair

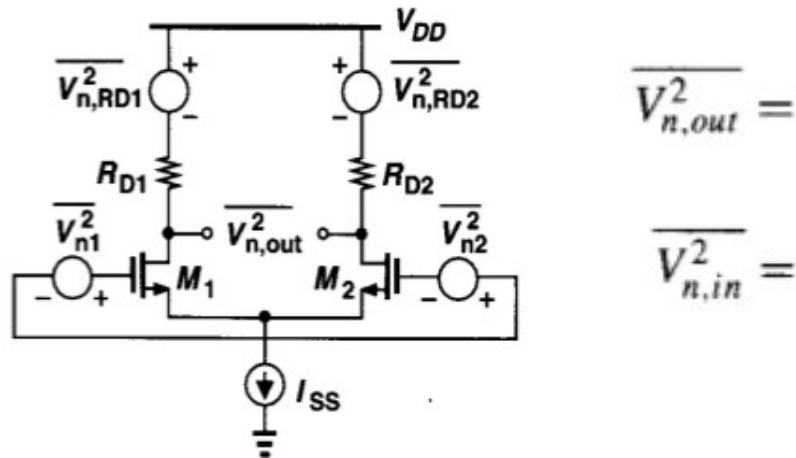
Consider differential signals



Since the four noise generators are uncorrelated, we can use superposition for the powers. Noise from  $M_1$ :



# Differential Pair



Thus, the input-referred noise voltage of a diff pair is 40% larger than that of a common-source stage – probably the only disadvantage of differential operation.

## Noise from $I_{SS}$

- Common-mode disturbance
- Modulation of  $g_m$  and therefore voltage gain